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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		APPLICANT(S) Makoto IIDA, Masanori KIMURA	
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U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
		JP A 10-50715	02-20-1998	Japan		
		JP A 11-307747	11-05-1999	Japan		
		JP A 11-260677	09-24-1999	Japan		
		JP A 2000-7486	01-11-2000	Japan		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)	
	M. Iida et al., "EFFECTS OF LIGHT ELEMENT IMPURITIES ON THE FORMATION OF GROWN-IN DEFECTS FREE REGION OF CZOCHRALSKI SILICON SINGLE CRYSTAL", Electrochemical Society Proceedings, Vol 99-1, pp. 499-510
	Wataru Ohashi et al., "Chisso Tenka CZ-Si Kesshou Kekkan Seigyo (No. 1)", March 28, 1999, Dai 46 kai, Oyou Butsurigaku Kankei Rengou Kouenkai Kouen Yokoshu (Ouyou Butsur Gakkai, Tokyo) p. 468, middle paragraph separate Vol 1.

EXAMINER	DATE CONSIDERED
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